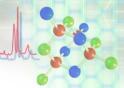


Spectrophotometer

V-700 series



V-700 Series UV-Vis/NIR Spectrophotometers





V-730

- SBW=1.0 nm
- Class-leading high S/N

V-730BIO

New iRM & Spectra Manager



V-750/760/770

 Wavelength-independent dynamic range

V-780 New!

 Highly sensitive measurement in NIR



New Features

1. Wavelength-independent dynamic range

V-750/760/770/780

2. High resolution as 1.0 nm bandwidth

V-730

3. High signal to noise ratio

V-730/750/760/770/780

4. New model: High sensitivity in NIR

V-780

5. Wide dynamic range in NIR

V-770/780

6. Stable measurement platform

V-730/750/760/770/780

7. Alignment-free lamp replacement

V-730/750/760/770/780

8. Spectra Manager II & CFR

V-730/750/760/770/780

9. iRM-1000

V-730/750/760/770/780

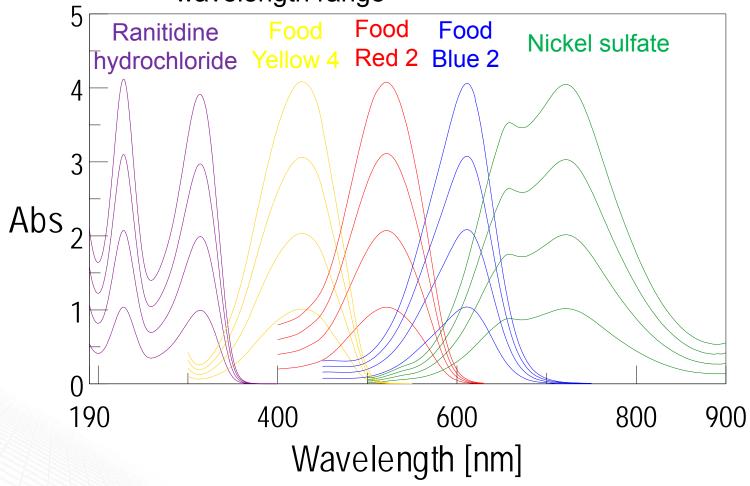
10. Upgraded accessories

V-730/750/760/770/780

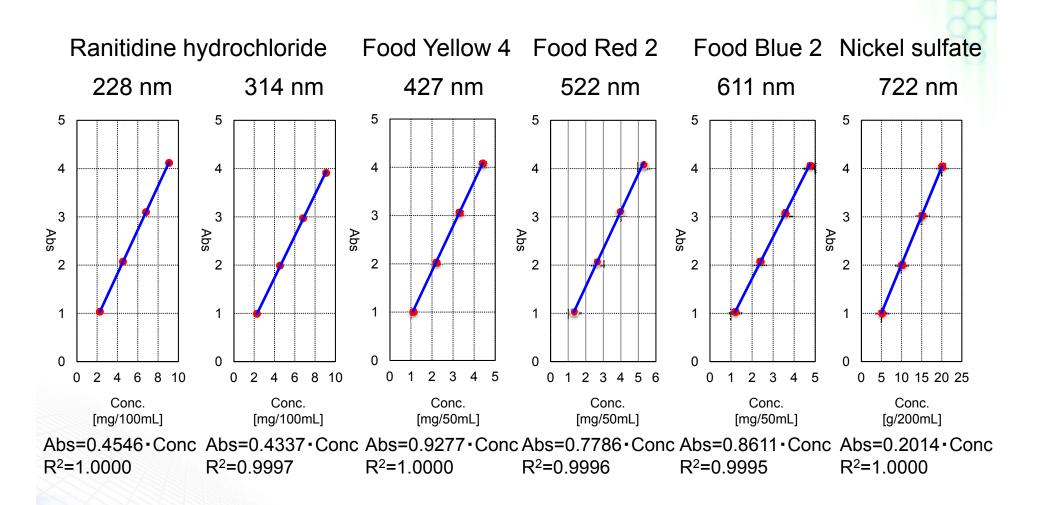


V-750/770/780

Linearity up to 4 absorbance in wide UV-Vis wavelength range



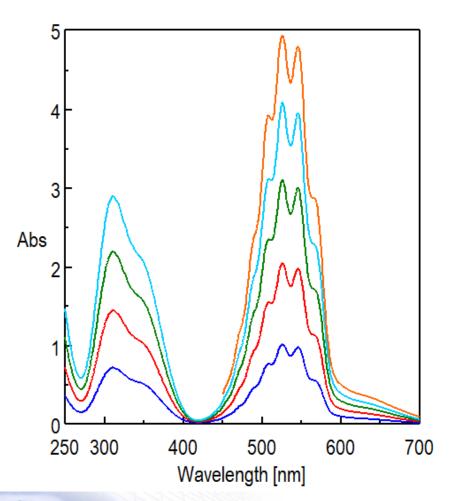


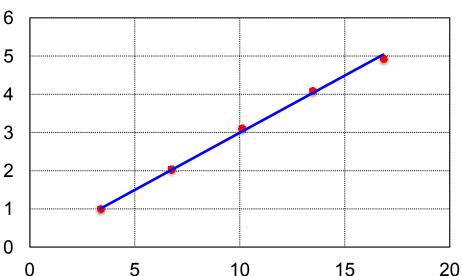




V-750/770/780

Excellent linearity up to 5 absorbance using KMnO₄ solution



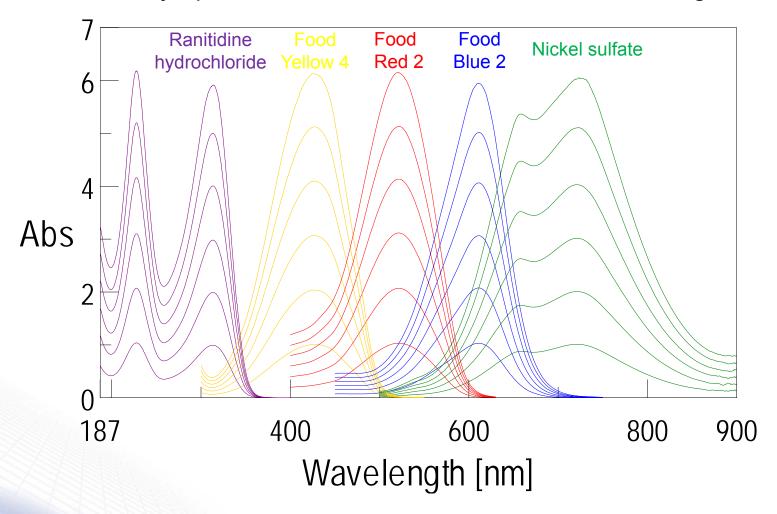


Abs=0.2993 • Conc R²=0.9977

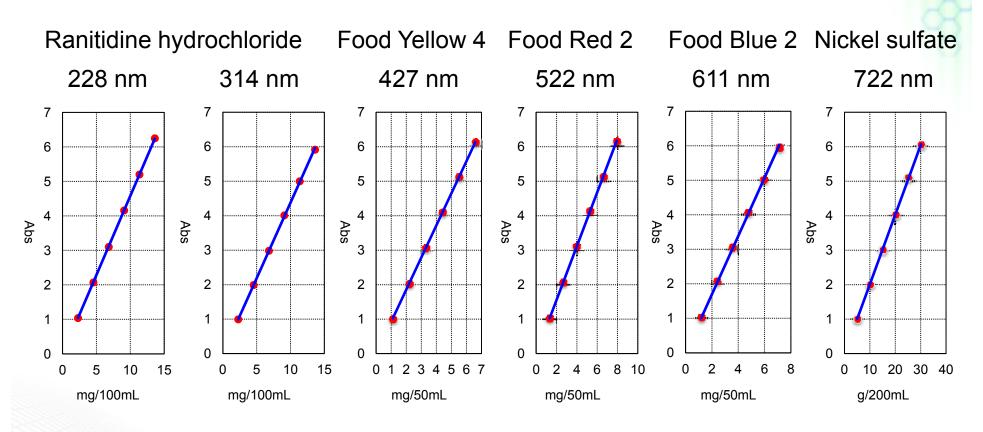


V-760

Linearity up to 6 absorbance in wide UV-Vis wavelength range





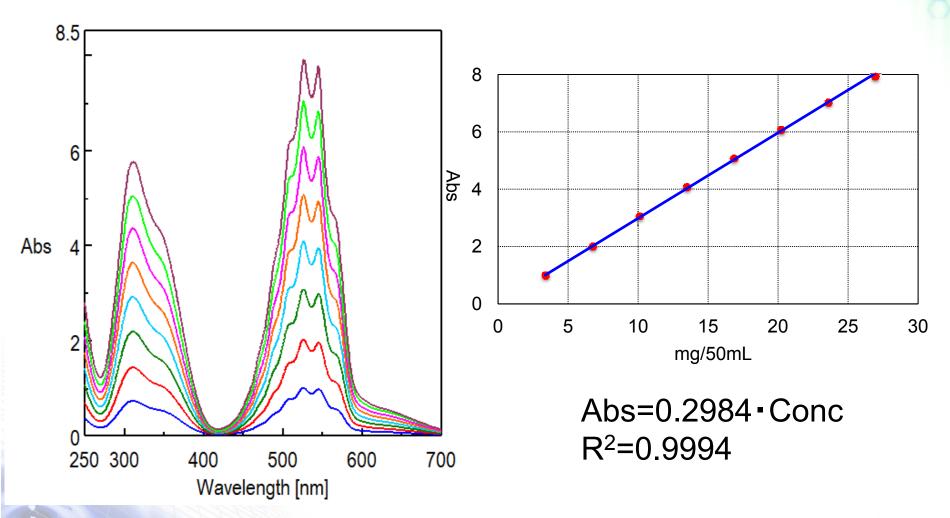




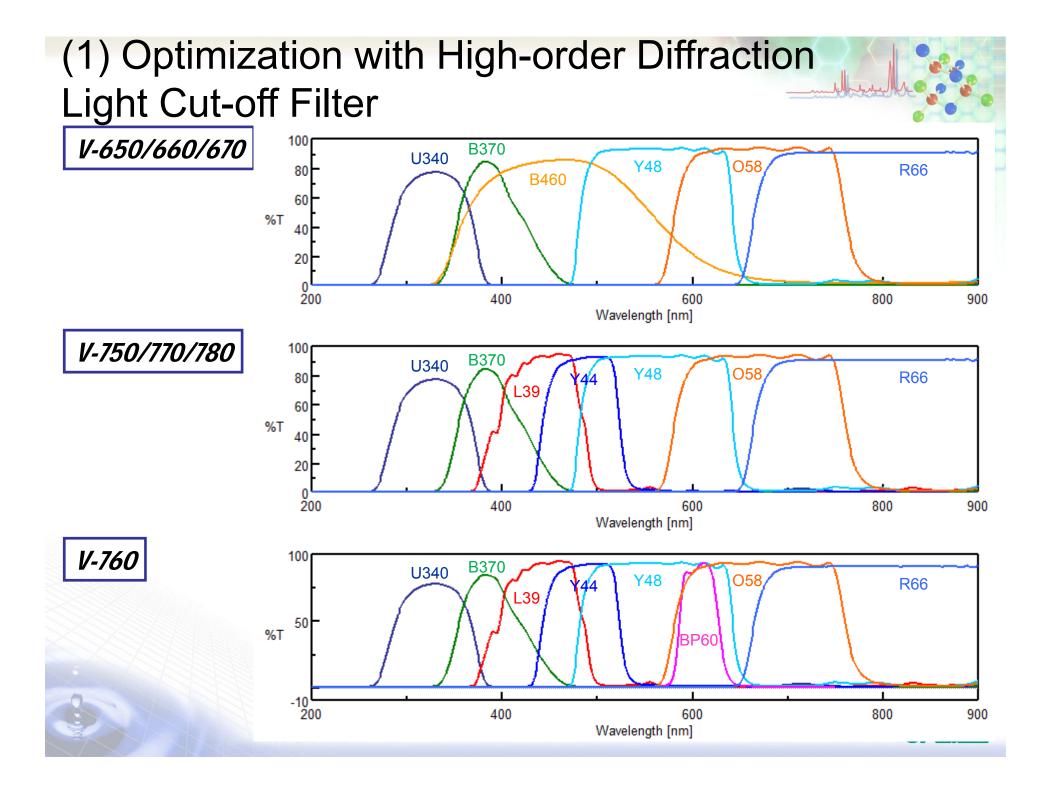


V-760

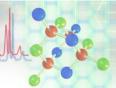
Excellent linearity up to 8 absorbance using KMnO₄ aqueous solution





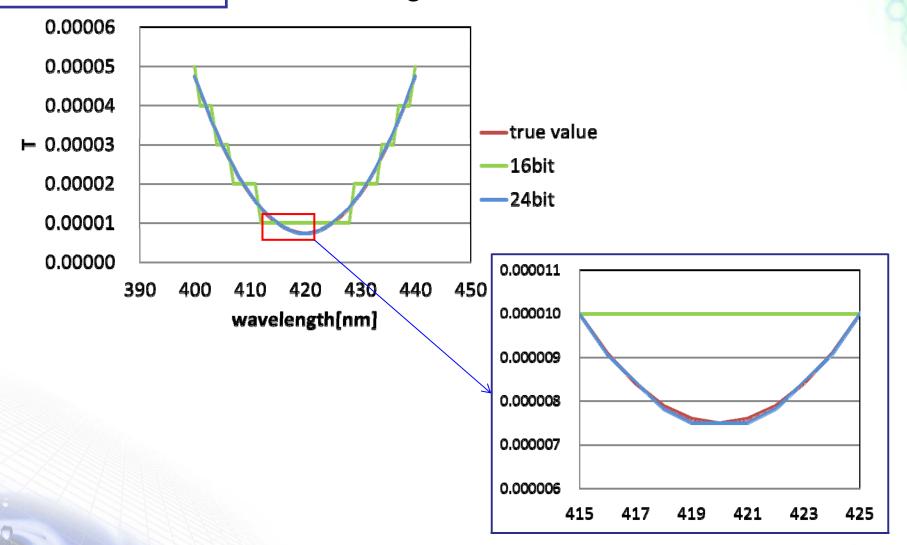


(2) Ultra-high Resolution ADC, 24 bit



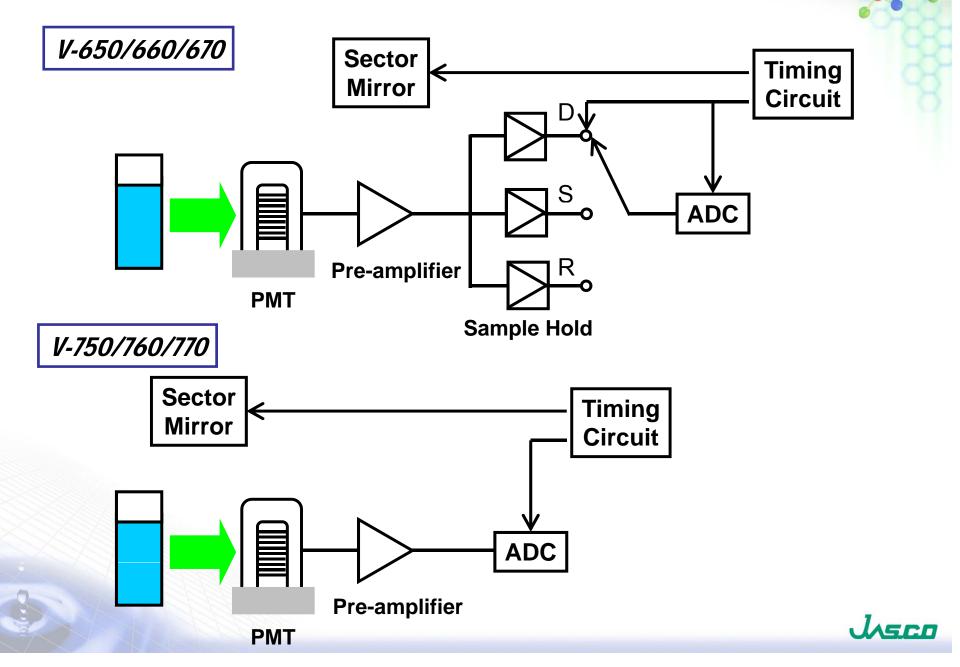
V-750/760/770/780

32-times higher resolution than 18 bit in V-600





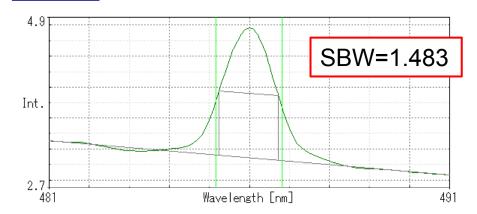
(3) Offset-free Signal acquisition in S, R, D



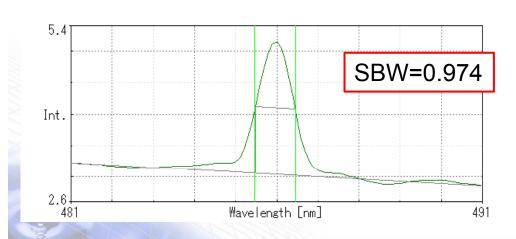
2. High resolution as 1.0 nm bandwidth

Emission line of D₂ lamp

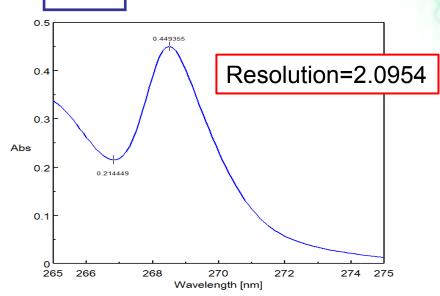




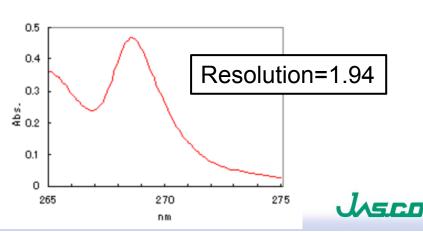
V-730



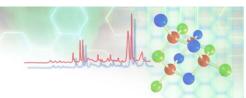
Resolution test of EP -Toluene/Hexane



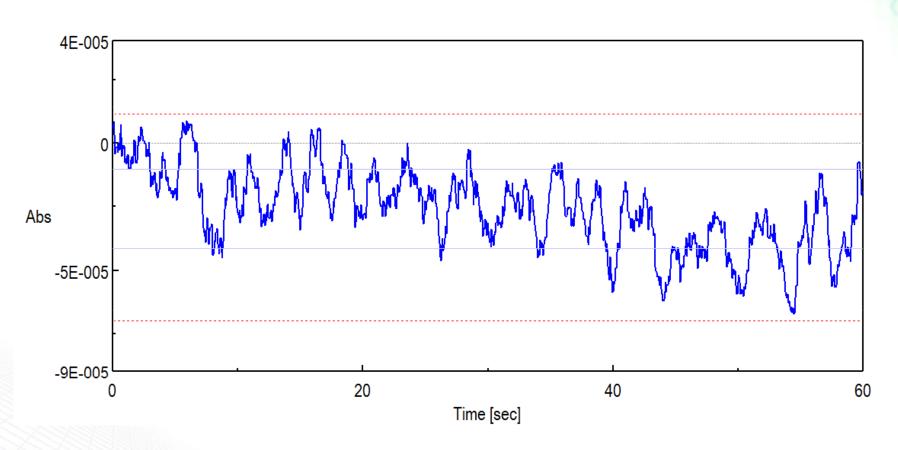
Shimazu UV-1800



Noise Level of V-730



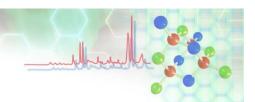
Specification RMS Noise≦0.00004 Abs



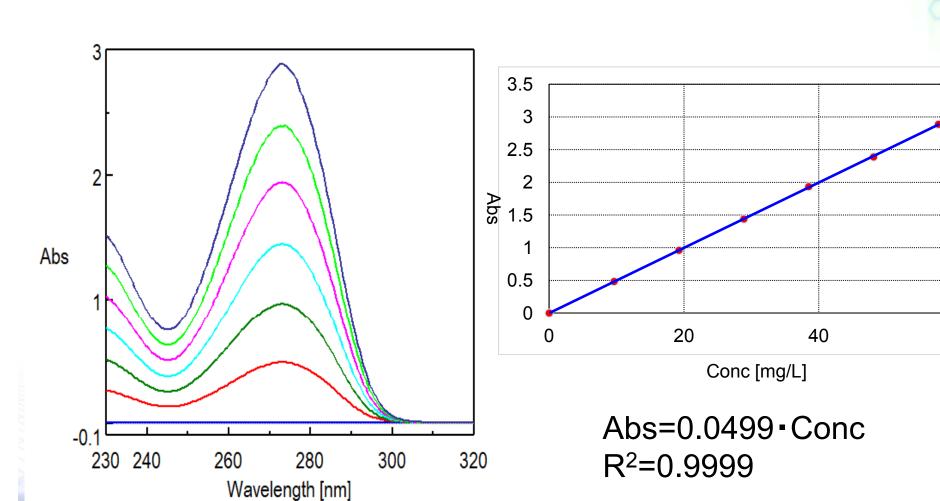
RMS Noise=0.000016 → Pass



Dynamic Range of V-730



Abs 3 with caffeine aqueous solution

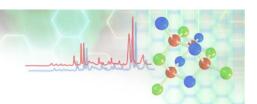




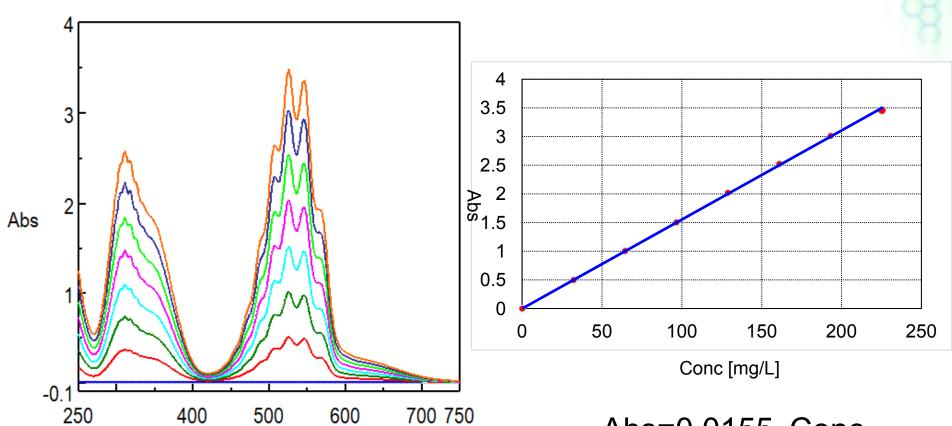
60

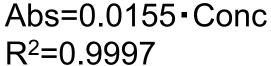
Dynamic Range of V-730

Wavelength [nm]



Abs 3.5 with KMnO₄ aqueous solution



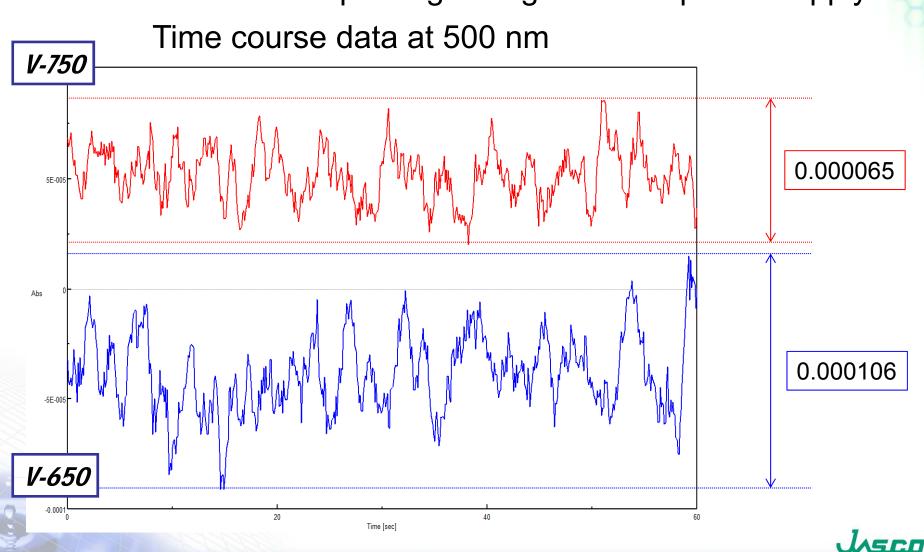




3. High signal to noise ratio

V-730/750/760/770/780

Enhanced signal-to-noise ratio by improving the light source power supply

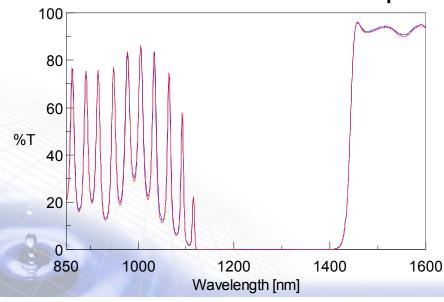


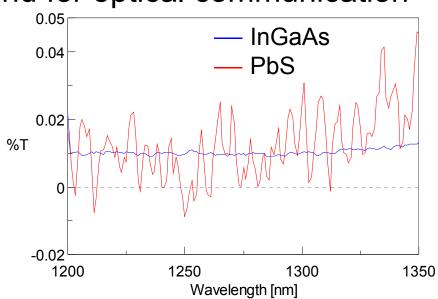


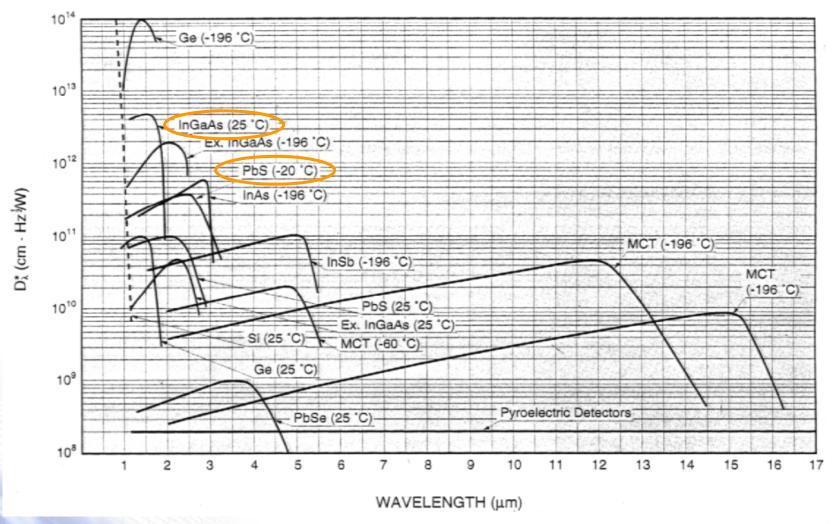
| Optical System | Single monochromator, Czerny-Turner mount Double beam type |
|-----------------------|--|
| Light Sources | Deuterium lamp, Halogen lamp |
| Grating | UV/VIS: 1200 lines/mm plane grating NIR: 600 lines/mm plane grating |
| Detector | Photomultiplier tube, Peltier cooled InGaAs detector |
| Wavelength Range | 190 to 1600 nm |
| Spectral Bandwidth | UV/VIS:0.1, 0.2, 0.5, 1, 2, 5, 10, L2, L5, L10, M1, M2 nm NIR:0.2, 0.4, 1, 2, 4, 10, 20, L4, L10, L20, M2, M4 nm |

High S/N in NIR

Cut-off filter for 1.3 µm band for optical communication



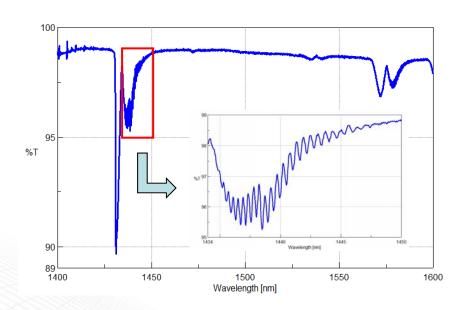


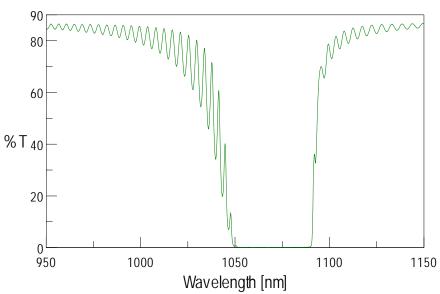




High resolution in NIR

The vibration spectrum of CO₂ The spectrum of NIR notch filter

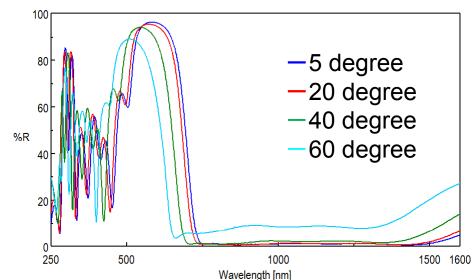






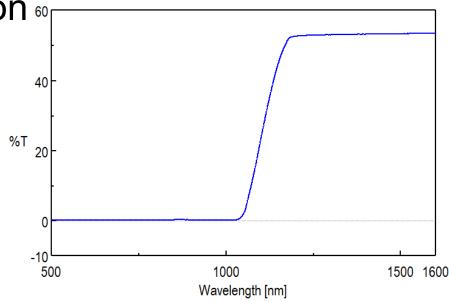
- New accessories
 - Integrating sphere
 - Absolute reflectance measurement unit

Absolute reflectance spectrum of anti-reflection coat for NIR

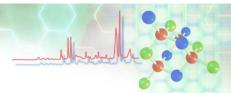


A wide variety of application
 Band gap measurement of Si

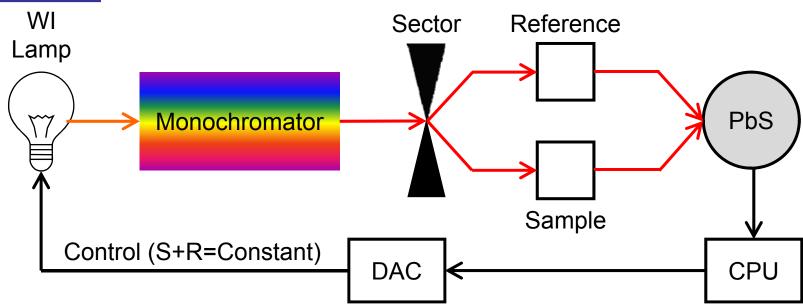
Band Gap=1.13 eV



5. Wide dynamic range in NIR



V-770/780 Brightness control of light source by digital feedback

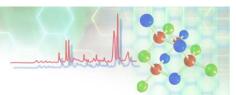


Outdated instruments (not V-600):

- The bandwidth and gain could only be adjusted for the optical signal in NIR.
- To obtain the stable optical signal intensity, the bandwidth could be changed depending on the wavelength to be used but the high resolution could not obtain in low-energy range of light sources.
- For the instrument with the fixed bandwidth, if the bandwidth is too large, the optical signal may be saturated depending on the wavelength to be used.

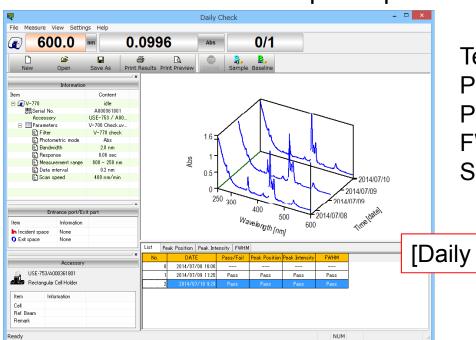


6. Stable Measurement Platform



V-730/750/760/770/780

Holmium glass filter is used for checking the spectrophotometer performance everyday.



Test items:

Peak position→Wavelength accuracy

Peak intensity→Photometric accuracy

FWHM→Resolution

Spectrum comparison

→Overall spectrum profile

[Daily check] program

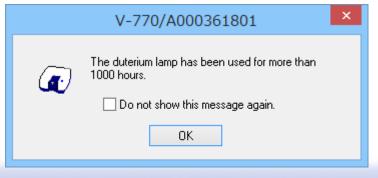
Display of message when D2 and WI lamps has been used for more than 1000

hours (New!)

Validation program

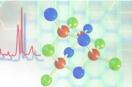
Instrument self-diagnosis function

Display of lamp operation time



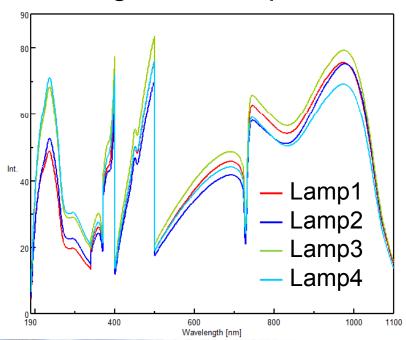


7. Alignment-free Lamp Replacement



The design of the socket deuterium lamp and socket tungsten halogen lamp facilitates light source over replacement, simplifies maintenance and reduces operation error.

Single beam spectra

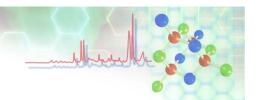


Validation results

| Inspection Items | 1 | 2 | 3 | 4 |
|------------------------|------|------|------|------|
| Wavelength Accuracy | Pass | Pass | Pass | Pass |
| Photometric Accuracy | Pass | Pass | Pass | Pass |
| Noise Level | Pass | Pass | Pass | Pass |
| Baseline Flatness | Pass | Pass | Pass | Pass |



8. Spectra Manager II & CFR

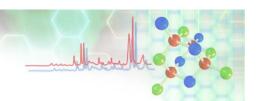








Standard Programs



Measurement Programs

Spectra Measurement (Improved!)

Quantitative Analysis (Improved!)

Time Course Measurement

Dual-Wavelength Time Course Measurement (New!)

Parallel Time Course Measurement (Cell Changer)

Fixed Wavelength Measurement

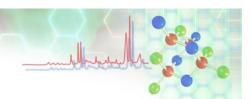
Abs/%T Meter

Validation (Improved!)

Daily Check (New!)



Standard Programs



| Analy | ysis | Prog | rams |
|-------|------|------|------|
|-------|------|------|------|

Spectra Analysis

JASCO Canvas

Enzymatic Reaction Rate Calculation

Film Thickness Analysis

Color Analysis (Compatible with international standards!)

X-Unit Conversion Photon

Time-Axis Offset

Peak Normalization

UV/Vis Kramers-Kronig Transform

Channel Conversion

Data Dump

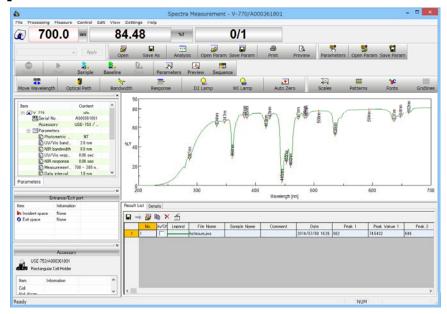
Data Accumulation

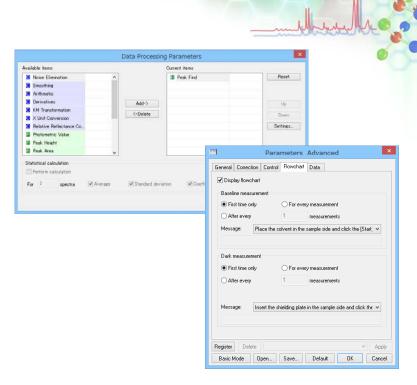
Arithmetic between Channels

Arithmetic between Data



Spectra Measurement





Data processing functions

Correction: Noise elimination, smoothing, arithmetic operations, derivatives, KM transform, x-axis conversion, relative reflectance correction Result display: Photometric value, peak detection, peak area, FWHM, spectrum comparison, quick quantitation, film thickness calculation

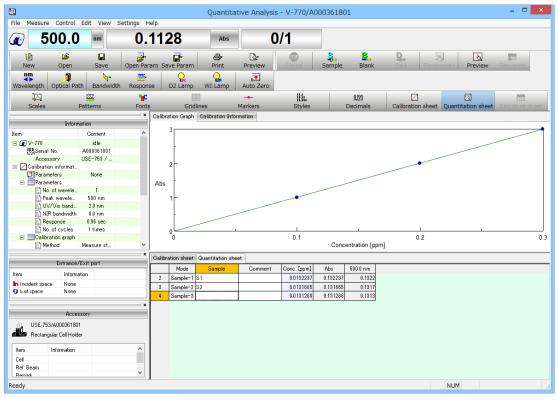
Statistical calculations

Statistical calculations (average, standard deviation, coefficient of variation) can also be performed for a specified number of measurements.

- Sequential measurements
- Flowchart measurement
- Autosampler available



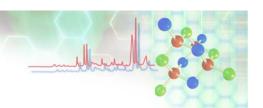
Quantitative Analysis

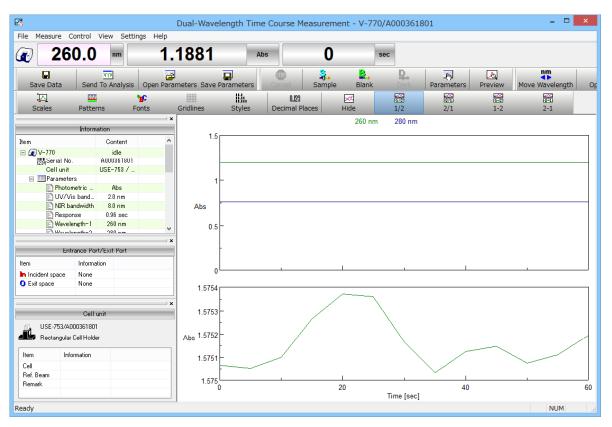


- Quantitative analysis (from creating the calibration curve to performing the quantitative analyses) can be performed using one program package
- Sequential measurements
- Autosampler available



Dual-Wavelength Time Course Measurement





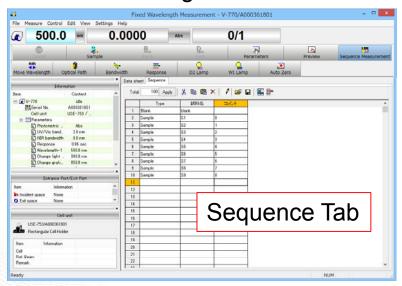
- •Kinetics measurement can be performed by dual wavelength.
- •The difference between dual photometric value and the ratio of dual photometric value can be plotted.



Expanded Functions

Sequential measurements

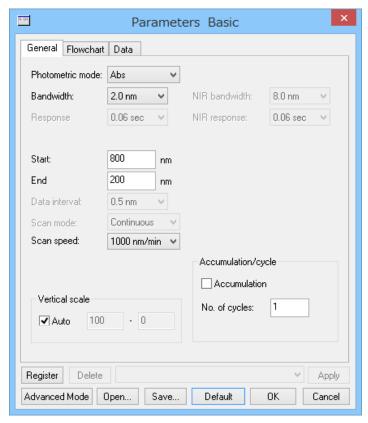
Measurements can be performed using a sequence sheet in which measurement types, sample names and comments are specified. The sequence sheet can be saved and utilized again.



Programs

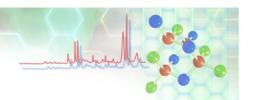
- Spectra Measurement
- Quantitative Analysis
- Fixed Wavelength Measurement

Enhanced Basic mode



The response time is automatically determined depending on the selected bandwidth and scan speed so that the spectrum profile does not become broad.

The data interval is also automatically determined depending on the selected bandwidth.



Programs for Biochemical Applications

Protein Nucleic Acid Measurement (Improved!)

Kinetics Analysis

Temperature Control Measurement (Improved!)

Programs for Quantitation

Spectrum Quantitative Measurement (New!)

Spectrum Quantitation

CLS Quantitative Measurement

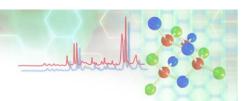
PCR Quantitative Measurement

PLS Quantitative Measurement

PCA

Chromaticity/Turbidity Measurement (Compatible with international standards!)





Programs for Versatile Applications

Interval Scan Measurement

Temperature Interval Measurement

Macro Command

Program Name for Color Analysis

Color Diagnosis (Compatible with international standards!)

Color Matching

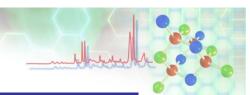
Color Matching for Color Materials

Luminous Color Measurement

ASTM Color Analysis

Saybolt Color Analysis





Programs for Material Analysis

Solar Transmittance/Reflectance Calculation (Compatible with international standards!)

Solar Transmittance/Reflectance Measurement (Compatible with international standards!)

Sample Haze Calculation (Compatible with international standards!)

UPF Calculation (Compatible with international standards!)

UPF Measurement (Compatible with international standards!)

Absolute Reflectance Spectra Measurement

Absolute Reflectance with Variable Incident Angle Measurement

Phase Difference Spectra Measurement

Multi-Layer Film Thickness Analysis

UV Shield Factor Calculation

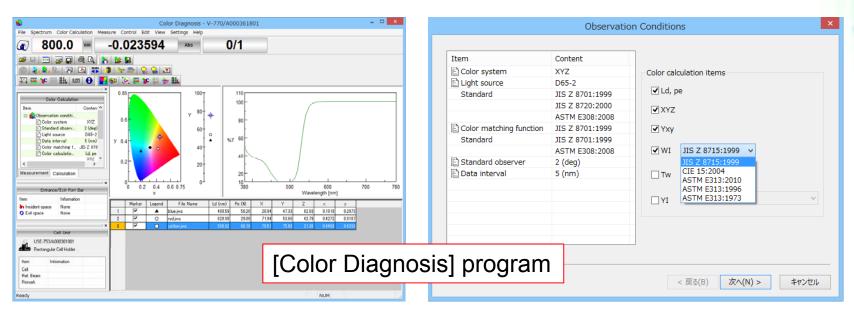
Band Gap Calculation

Film Thickness and Refractive Index

Average Reflectance Calculation



Compatible with International Standards

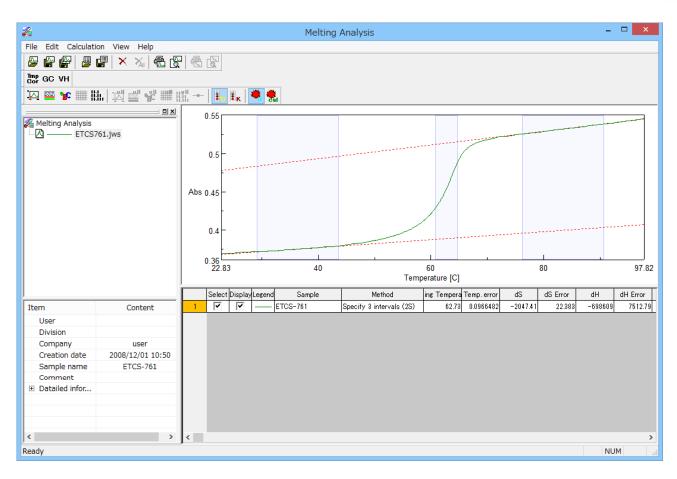


Programs

- Color Analysis
- Chromaticity/Turbidity Measurement
- Color Diagnosis
- Solar Transmittance/Reflectance Calculation
- Solar Transmittance/Reflectance Measurement
- Sample Haze Calculation
- UPF Calculation
- UPF Measurement



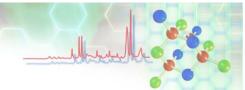
Enhanced DNA Melting Analysis Program



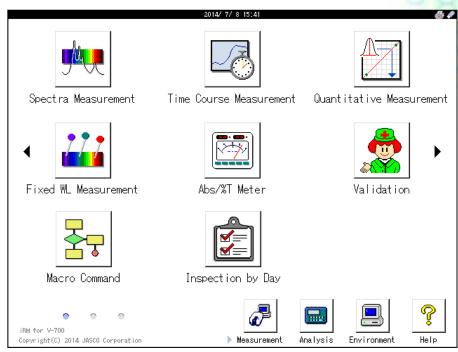
- Not just Tm and ΔH, ΔS can be calculated
- Fitting method or van't Hoff plot method can be selected



9. iRM-1000







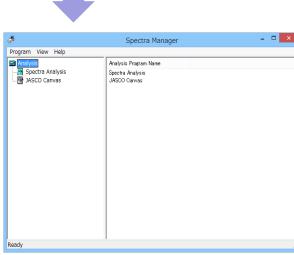
- USB memory available
- Analysis programs for DS type are installed as default
- Enriched standard programs
- Increased applicable printers



iRM data can be moved to Spectra Manager using USB flash drive







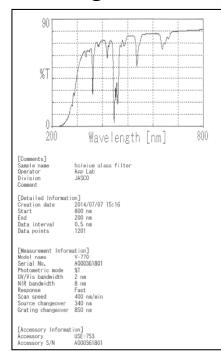
Analysis programs for PC type are as standard



Increased Applicable Printers

- Thermal printer in wide width, enabling the print of spectrum
- Non-thermal type of compact printer

Print image of Printy4



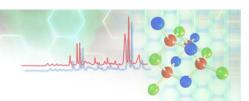
Support of color printing by ESC/P-R



EPSON Printer (compatible with ESC/P-R)



Standard Programs



Measurement Programs

Spectra Measurement

Quantitative Measurement

Time Course Measurement

Fixed Wavelength Measurement

Macro Command

Abs/%T Meter

Validation program

Daily Check (New!)

Analysis Programs

Spectra Analysis

Enzymatic Reaction Rate Calculation

Film Thickness Analysis

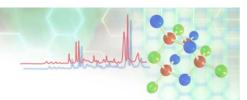
Color Analysis program



| Name | Components |
|-------------|---|
| Bio Package | Protein Nucleic Acid Measurement (Improved!) |
| | Parallel Time Course Measurement (Cell Changer) |
| | Kinetics Analysis |
| | Temperature Control Measurement |
| | DNA Melting Analysis |



10. Updated Accessories

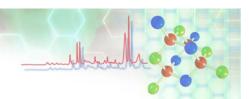


Compatible with V-500/600 series accessories

| Model No. | Name |
|---|---|
| NQF-781 | Vacuum Sipper |
| NPF-782 | Peristaltic Sipper |
| NQF-783 | Vacuum Sipper with Long-Path Cell |
| ISV-922/ISN-923/ <mark>ISN-901i</mark> | 60-mm Integrating Sphere |
| ILV-924/ILN-925/ <mark>ILN-902</mark> i | 150-mm Integrating Sphere |
| PIN-903i | Horizontal Sampling Integrating Sphere |
| ARV-913/ARN-914/ARN-915i | Absolute Reflectance Measurement Unit (synchronous) |
| ARSV-916/ARSN-917/ARSN- | Absolute Reflectance Measurement Unit |
| 918i | (asynchronous) |
| ARMV-919/ARMN-920/ARMN- | Automated Absolute Reflectance |
| 921i | Measurement Unit |
| SLM-907 | Specular Reflection Unit |
| SLM-908 | Specular Reflection Unit |
| OLIVI OOO | (accommodating 6-inch silicon wafers) |



10. Upgraded Accessories



NQF-781 Vacuum Sipper



Space-saving

Absolute Reflectance Measurement Unit



USB communication Improved sample compartment lid

ISV-922/ISN-923/ISN-901i 60-mm¢ Integrating Sphere





Improved sample holder



Conclusion





Class-leading specification



 Quite satisfactory function of Bio market



V-750/760/770

 Wavelength-independent dynamic range

V-780 New!

 Highly sensitive measurement in NIR

